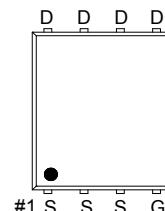
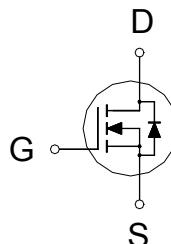


**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P5515BK**  
**PDFN 5x6P**  
**Halogen-Free & Lead-Free**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
150V	55mΩ	13.4A


G. GATE  
D. DRAIN  
S. SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	150	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	13.4	A
	$T_C = 100^\circ\text{C}$		8.5	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	31	A
Continuous Drain Current	$T_A = 25^\circ\text{C}$	$I_D$	4.1	
	$T_A = 70^\circ\text{C}$		3.3	
Avalanche Current		$I_{AS}$	15.8	
Avalanche Energy	$L = 1\text{mH}$	$E_{AS}$	125	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	24	W
	$T_C = 100^\circ\text{C}$		9.6	
Power Dissipation	$T_A = 25^\circ\text{C}$	$P_D$	2.2	W
	$T_A = 70^\circ\text{C}$		1.4	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$		54	°C / W
Junction-to-Case	$R_{\theta JC}$		5.2	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ .

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ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

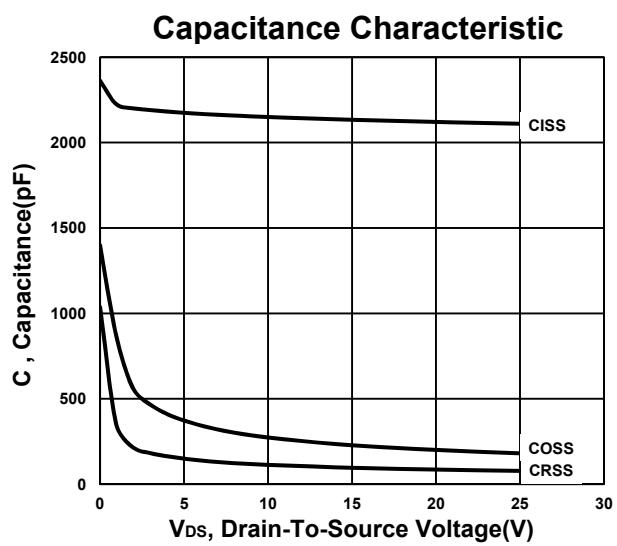
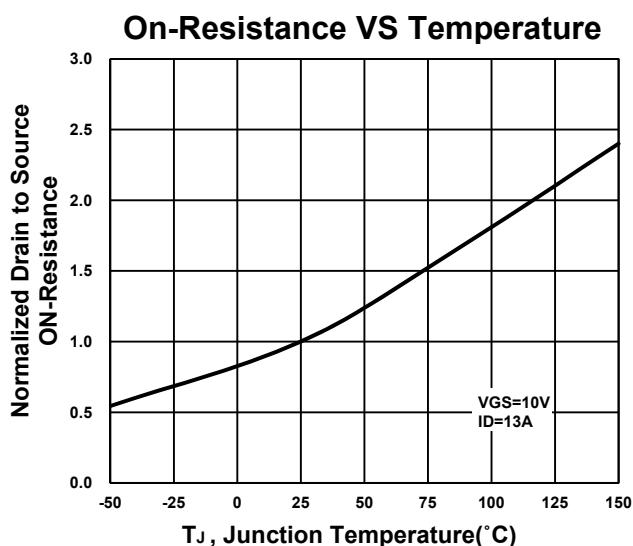
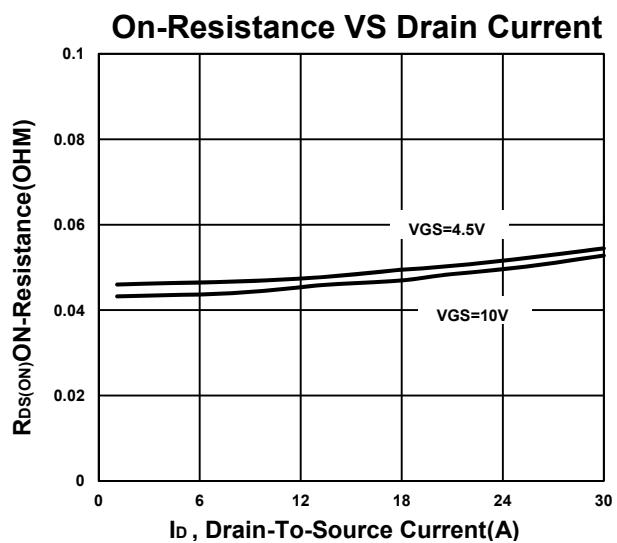
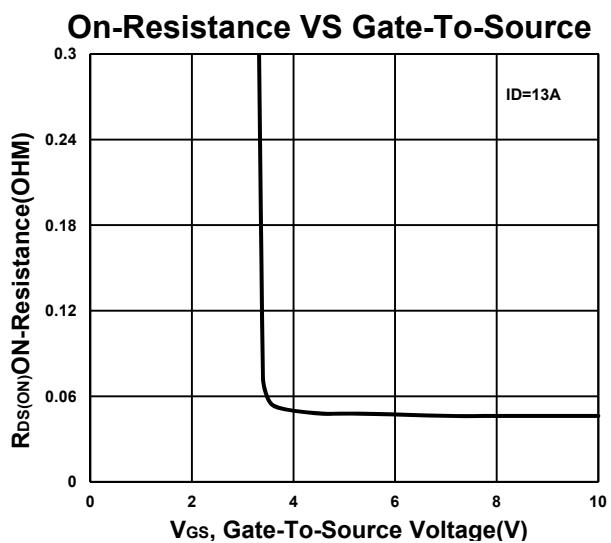
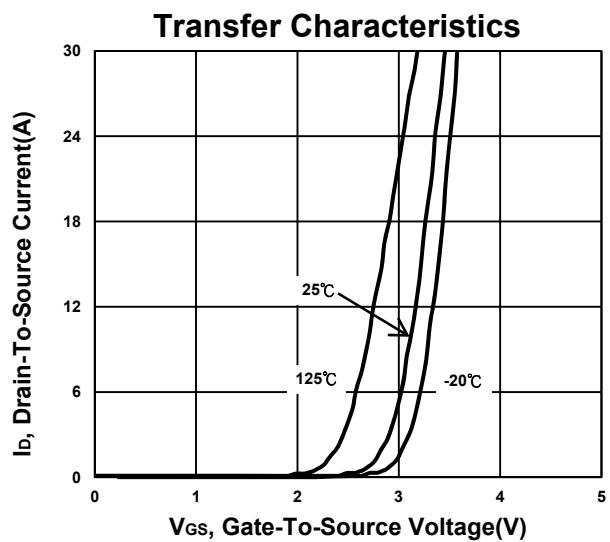
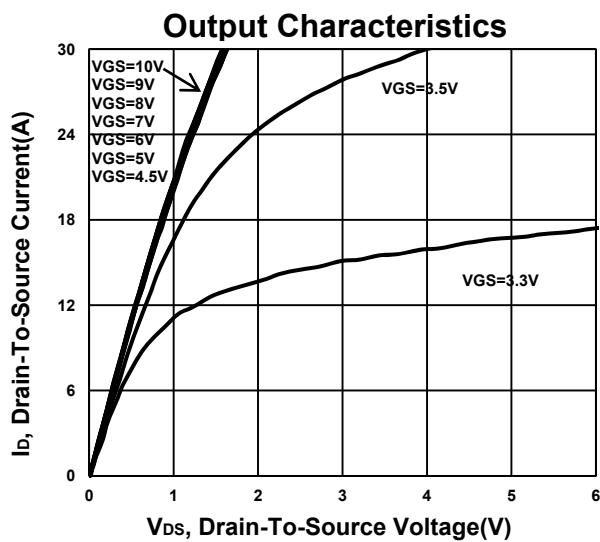
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	150			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.3	1.75	2.3	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 120\text{V}, V_{\text{GS}} = 0\text{V}$			1	$\mu\text{A}$
		$V_{\text{DS}} = 100\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 10\text{A}$		47	65	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 13\text{A}$		46	55	
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 5\text{V}, I_D = 13\text{A}$		76		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		2103		pF
Output Capacitance	$C_{\text{oss}}$			180		
Reverse Transfer Capacitance	$C_{\text{rss}}$			77		
Gate Resistance	$R_g$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.3		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{\text{GS}} = 10\text{V}$		41		nC
		$V_{\text{GS}} = 4.5\text{V}$		21		
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$	$V_{\text{DS}} = 75\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 13\text{A}$		5.9		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$			10.6		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$			18		
Rise Time <sup>2</sup>	$t_r$			18		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$	$V_{\text{DS}} = 75\text{V}, I_D \approx 13\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 6\Omega$		68		
Fall Time <sup>2</sup>	$t_f$			45		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				13.4	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = 13\text{A}, V_{\text{GS}} = 0\text{V}$			1	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = 13\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		55		nS
Reverse Recovery Charge	$Q_{\text{rr}}$			93		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

**NIKO-SEM**

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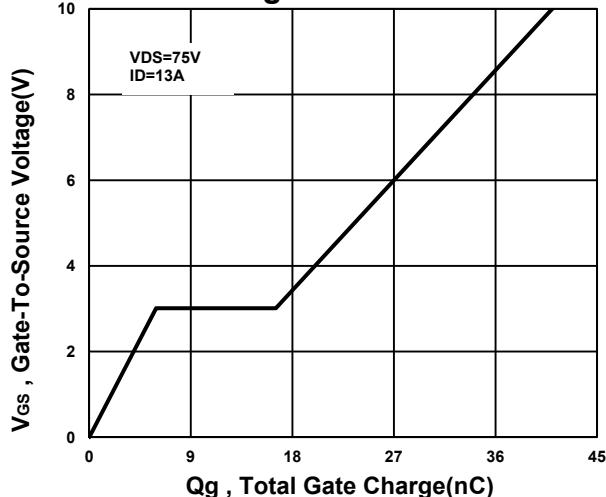


**NIKO-SEM**

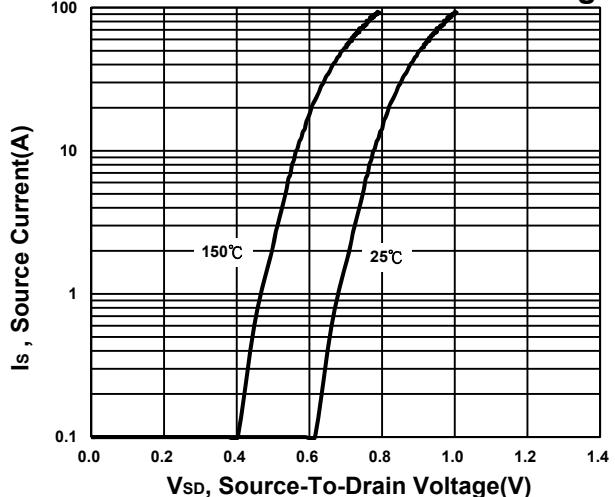
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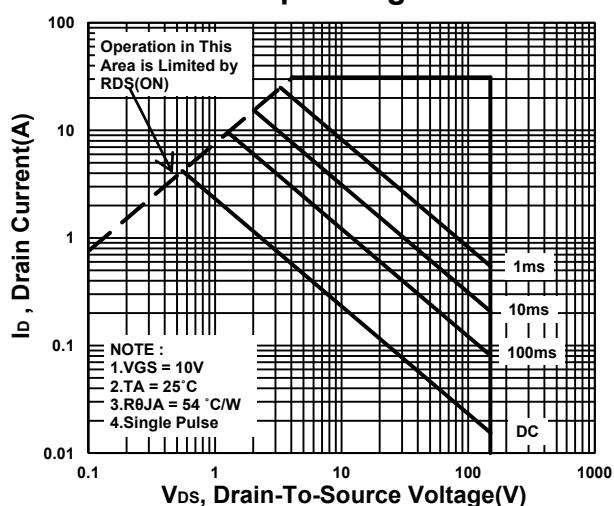
### Gate charge Characteristics



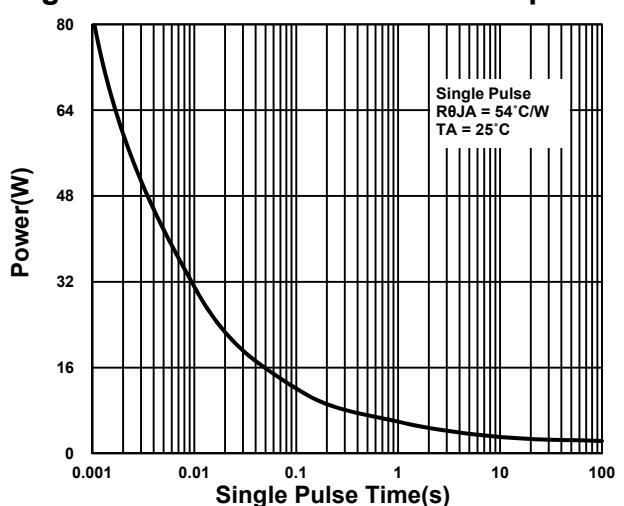
### Source-Drain Diode Forward Voltage



### Safe Operating Area



### Single Pulse Maximum Power Dissipation



### Transient Thermal Response Curve

